# STF25N60M2-EP

## N-channel 600 V, 0.175 Ω typ., 18 A MDmesh™ M2 EP Power MOSFET in a TO-220FP package

Datasheet - production data



life.augmented

Figure 1: Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max.	ID
STF25N60M2-EP	650 V	0.188 Ω	18 A

- Extremely low gate charge
- Excellent output capacitance (Coss) profile
- Very low turn-off switching losses
- 100% avalanche tested
- Zener-protected

### **Applications**

- Switching applications
- Tailored for Very High Frequency Converters (f > 150 kHz)

### Description

This device is an N-channel Power MOSFET developed using MDmesh<sup>™</sup> M2 EP enhanced performance technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance, optimized switching characteristics with very low turn-off switching losses, rendering it suitable for the most demanding very high frequency converters.

#### Table 1: Device summary

Order code	Marking	Package	Packaging
STF25N60M2-EP	25N60M2EP	TO-220FP	Tube

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This is information on a product in full production.

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### 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate-source voltage	± 25	V
ID	Drain current (continuous) at $T_C = 25 \text{ °C}$	18 <sup>(1)</sup>	А
ID	Drain current (continuous) at T <sub>C</sub> = 100 °C	11.3 <sup>(1)</sup>	А
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	72 <sup>(1)</sup>	А
P <sub>TOT</sub>	Total dissipation at $T_C = 25 \ ^{\circ}C$	30	W
dv/dt <sup>(3)</sup>	Peak diode recovery voltage slope	15	V/ns
dv/dt <sup>(4)</sup>	MOSFET dv/dt ruggedness	50	V/ns
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s, $T_C = 25$ °C)	2500	V
T <sub>stg</sub>	Storage temperature	55 to 150	°C
Tj	Max. operating junction temperature	- 55 to 150	C

#### Notes:

 $\ensuremath{^{(1)}}\xspace$  Limited by maximum junction temperature.

 $^{\rm (2)} {\rm Pulse}$  width limited by safe operating area.

<sup>(3)</sup> $I_{SD} \le 18$  A, di/dt  $\le 400$  A/µs; V<sub>DS peak</sub> < V<sub>(BR)DSS</sub>, V<sub>DD</sub> = 400 V.

 $^{(4)}V_{DS} \le 480 \text{ V}$ 

#### Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	4.2	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max	62.5	°C/W

#### Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive (pulse width limited by T <sub>jmax</sub> )	3.5	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j$ = 25 °C, $I_D$ = $I_{AR};$ $V_{DD}$ = 50 V)	200	mJ



 $T_C = 25$  °C unless otherwise specified

Table 5: On/off states							
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS}$ = 0 V, $I_D$ = 1 mA	600			V	
	Zoro goto voltago Droin	$V_{GS} = 0 \text{ V}, \text{ V}_{DS} = 600 \text{ V}$			1	μA	
I <sub>DSS</sub> Zero gate voltag current	Zero gate voltage Drain current	$V_{GS} = 0 V, V_{DS} = 600 V,$ $T_{C} = 125 \text{ °C}$			100	μA	
I <sub>GSS</sub>	Gate-body leakage current	$V_{DS}$ = 0 V, $V_{GS}$ = ±25 V			±10	μA	
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS}=V_{GS},\ I_{D}=250\ \mu A$	2	3	4	V	
R <sub>DS(on)</sub>	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 9 \text{ A}$		0.175	0.188	Ω	

Table 6: Dynamic						
Symbol	SymbolParameterTest conditionsMin.Typ.Max.					Unit
C <sub>iss</sub>	Input capacitance		-	1090	-	pF
C <sub>oss</sub>	Output capacitance	$V_{DS}$ = 100 V, f = 1 MHz,	-	56	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	$V_{GS} = 0 V$	-	1.6	-	pF
Coss eq. <sup>(1)</sup>	Equivalent output capacitance	$V_{DS}$ = 0 to 480 V, $V_{GS}$ = 0 V	-	255	-	pF
R <sub>G</sub>	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	7	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 18 A,	-	29	-	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V (see <i>Figure 16:</i>	-	6	-	nC
$Q_gd$	Gate-drain charge	"Gate charge test circuit")	-	12	-	nC

#### Notes:

 $^{(1)}C_{oss~eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

**Table 7: Switching Energy** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
E <sub>(off)</sub>	Turn-off energy (from 90% V <sub>GS</sub> to 0% I <sub>D</sub> )		-	7	-	μJ
			-	8	-	μJ



	Table 8: Switching times						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 300 \text{ V}, \text{ I}_{D} = 9 \text{ A}$	-	15	-	ns	
tr	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$ (see Figure 15: "Switching - times test circuit for	-	10	•	ns	
$t_{d(off)}$	Turn-off-delay time		-	61	•	ns	
t <sub>f</sub>	Fall time	resistive load" and Figure 20: "Switching time waveform")	-	16	-	ns	

#### Table 9: Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		18	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		72	А
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	$V_{GS} = 0 V, I_{SD} = 18 A$	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 18 A,	-	360		ns
Qrr	Reverse recovery charge	di/dt = 100 A/µs, V <sub>DD</sub> = 100 V (see <i>Figure</i>	-	5		μC
I <sub>RRM</sub>	Reverse recovery current	17: " Test circuit for inductive load switching and diode recovery times")	-	28		A
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 18 A,	-	445		ns
Qrr	Reverse recovery charge	di/dt = 100 A/µs, V <sub>DD</sub> = 100 V, T <sub>i</sub> = 150 °C	-	6.5		μC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 17: " Test circuit for inductive load switching and diode recovery times")	-	29		A

#### Notes:

 $\ensuremath{^{(1)}}\xspace\mathsf{Pulse}$  width is limited by safe operating area

 $^{(2)}$  Pulsed: pulse duration = 300  $\mu s,$  duty cycle 1.5%



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### 3 Test circuits







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### 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.



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## 4.1 TO-220FP package information



#### Package mechanical data

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Table 10: TO-220FP mechanical data					
Dim.		mm			
Din.	Min.	Тур.	Max.		
A	4.4		4.6		
В	2.5		2.7		
D	2.5		2.75		
E	0.45		0.7		
F	0.75		1		
F1	1.15		1.70		
F2	1.15		1.70		
G	4.95		5.2		
G1	2.4		2.7		
Н	10		10.4		
L2		16			
L3	28.6		30.6		
L4	9.8		10.6		
L5	2.9		3.6		
L6	15.9		16.4		
L7	9		9.3		
Dia	3		3.2		



## 5 Revision history

Table 11: Document revision history

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Date	Revision	Changes
02-Dec-2014	1	First release.
12-Jan-2015	2	Updated product status from "preliminary data" to "production data".
14-Jan-2015	3	Corrected product status information on cover page.



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